# Notice of References Cited Application/Control No. 10/549,591 Examiner HAI V. NGUYEN Applicant(s)/Patent Under Reexamination FUKUDA, KUNIO Art Unit Page 1 of 3

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,768,277 A	06-1998	Ohno et al.	370/457
*	В	US-5,802,105 A	09-1998	Tiedemann et al.	375/225
*	С	US-5,889,772 A	03-1999	Fischer et al.	370/346
*	D	US-6,256,334 B1	07-2001	Adachi, Hideo	375/132
*	Е	US-6,351,456 B1	02-2002	Struhsaker et al.	370/280
*	F	US-6,404,756 B1	06-2002	Whitehill et al.	370/338
*	G	US-2002/0083246 A1	06-2002	Rupp et al.	710/107
*	Ι	US-2002/0136183 A1	09-2002	Chen et al.	370/338
*	I	US-2002/0172186 A1	11-2002	Larsson, Peter	370/349
*	J	US-2002/0191567 A1	12-2002	Famolari et al.	370/335
*	K	US-2002/0193133 A1	12-2002	Shibutani, Akira	455/522
*	L	US-2003/0002680 A1	01-2003	Akiyama et al.	380/278
*	М	US-2003/0177379 A1	09-2003	Hori et al.	713/193

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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### **NON-PATENT DOCUMENTS**

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# Notice of References Cited Application/Control No. 10/549,591 Examiner HAI V. NGUYEN Applicant(s)/Patent Under Reexamination FUKUDA, KUNIO Art Unit 2618 Page 2 of 3

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0141468 A1	07-2004	Christensen et al.	370/252
*	В	US-2004/0152423 A1	08-2004	Reznik, Alexander	455/067.11
*	O	US-2004/0179537 A1	09-2004	Boyd et al.	370/395.54
*	D	US-2004/0179588 A1	09-2004	Kuffner et al.	375/224
*	Е	US-2004/0195311 A1	10-2004	Silverbrook et al.	235/375
*	F	US-2005/0063356 A1	03-2005	Larsen et al.	370/351
*	G	US-2005/0075124 A1	04-2005	Willenegger et al.	455/522
*	Ι	US-7,023,817 B2	04-2006	Kuffner et al.	370/324
*	-	US-7,035,917 B2	04-2006	Yamasita, Tetsuya	709/220
*	٦	US-7,177,294 B2	02-2007	Chen et al.	370/338
*	K	US-2007/0104171 A1	05-2007	KASAMI et al.	370/339
*	L	US-7,215,681 B2	05-2007	Li, Chris Cho-Pin	370/445
*	М	US-2007/0121706 A1	05-2007	Nakamura et al.	375/141

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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### **NON-PATENT DOCUMENTS**

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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. 10/549,591 Examiner HAI V. NGUYEN Applicant(s)/Patent Under Reexamination FUKUDA, KUNIO Art Unit Page 3 of 3

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,286,474 B2	10-2007	Garg et al.	370/230
*	В	US-2007/0282900 A1	12-2007	Owens et al.	707/104.1
*	O	US-2008/0076465 A1	03-2008	Larsson, Peter	455/522
*	D	US-2008/0076466 A1	03-2008	Larsson, Peter	455/522
	Ш	US-			
	F	US-			
	G	US-			
	Ι	US-			
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	K	US-			
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### FOREIGN PATENT DOCUMENTS

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### **NON-PATENT DOCUMENTS**

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